

TRADEMARK ASSIGNMENT COVER SHEET

Electronic Version v1.1
Stylesheet Version v1.2

ETAS ID: TM337964

SUBMISSION TYPE:	NEW ASSIGNMENT		
NATURE OF CONVEYANCE:	RELEASE OF SECURITY INTEREST		
CONVEYING PARTY DATA			
Name	Formerly	Execution Date	Entity Type
Silicon Valley Bank		04/10/2015	CORPORATION: CALIFORNIA
RECEIVING PARTY DATA			
Name:	Aehr Test Systems		
Street Address:	400 Kato Terrace		
City:	Fremont		
State/Country:	CALIFORNIA		
Postal Code:	94539		
Entity Type:	CORPORATION: CALIFORNIA		
PROPERTY NUMBERS Total: 1			
Property Type	Number	Word Mark	
Registration Number:	1994800	DIEPAK KNOWN GOOD DIE SOLUTIONS	
CORRESPONDENCE DATA			
Fax Number:	7036106200		
<i>Correspondence will be sent to the e-mail address first; if that is unsuccessful, it will be sent using a fax number, if provided; if that is unsuccessful, it will be sent via US Mail.</i>			
Phone:	703-610-6100		
Email:	boxip@hoganlovells.com		
Correspondent Name:	Valerie Brennan, Hogan Lovells US LLP		
Address Line 1:	7930 Jones Branch Drive, 9th Floor		
Address Line 2:	Box Intellectual Property		
Address Line 4:	McLean, VIRGINIA 22102		
ATTORNEY DOCKET NUMBER:	002509.16		
NAME OF SUBMITTER:	Valerie Brennan		
SIGNATURE:	/vb/		
DATE SIGNED:	04/13/2015		
Total Attachments: 10			
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IN THE UNITED STATES
PATENT AND TRADEMARK OFFICE

RELEASE OF SECURITY INTEREST

[4 / 18], 2015

WHEREAS, Aehr Test Systems, a California corporation ("Assignee"), on August 21, 2013 granted a security interest in the federal trademark applications and registrations shown on the attached Schedule A (collectively, the "Marks") and the federal patents and patent applications shown on the attached Schedule B (collectively, the "Patents") and all of its other intellectual property (together with the Marks and Patents, collectively, the "Intellectual Property Collateral") to Silicon Valley Bank, a California corporation ("Assignor"), which security agreement was recorded with the United States Patent and Trademark Office with respect to patents at Reel/Frame 031171/0001 and with respect to trademarks, at Reel/Frame 5106/0126, respectively, on September 6, 2013, and subsequently at Reel/Frame 033743/0852 on September 16, 2014.

WHEREAS, Assignor desires to release its rights as a mortgagee, pledgee, and secured party in connection with the Intellectual Property Collateral under the aforementioned security agreement, and Assignee desires to accept the release of the security interest and lien on the Intellectual Property Collateral.

NOW THEREFORE, for good and valuable consideration paid by Assignee, receipt of which is hereby acknowledged, Assignor hereby releases the mortgage, pledge, and security interest in and to the Intellectual Property Collateral, releases all other rights it may have under said security agreement, and cancels such agreement, effective as of the date first set forth above.

[Signature page follows.]

IN WITNESS WHEREOF, Assignor has caused this Release to be duly executed as of the date first set forth above.

SILICON VALLEY BANK

By: _____

Name: _____

Title: _____

[Handwritten Signature]
[Handwritten Name: Vinod Patel]
[Handwritten Title: V.P.]

[Signature Page to IP Release of Security Interest]

SCHEDULE A
U.S. TRADEMARKS

Mark	Application/ Registration No.	Security interest
DIEPAK KNOWN GOOD DIE SOLUTIONS	1994800	Silicon Valley Bank Reel/Frame 5106/0126 Recorded 09/06/2013

SCHEDULE B
U.S. PATENTS

	Title	Application No. / Publication No. / Patent No.	Filing Date / Issue Date	Security Interest
1.	ADHESIVELY ATTACHED STAND-OFFS ON A PORTABLE PACK FOR AN ELECTRONICS TESTER	13474581 20120223729	05/17/2012	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
2.	APPARATUS FOR TESTING ELECTRONIC DEVICES	11413323 7762822	04/27/2006 07/27/2010	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
3.	APPARATUS FOR TESTING ELECTRONIC DEVICES	11522216 7826995	09/14/2006 11/02/2010	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
4.	APPARATUS FOR TESTING ELECTRONIC DEVICES	12772932 8118618	05/03/2010 02/21/2012	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
5.	APPARATUS FOR TESTING ELECTRONIC DEVICES	13353269 8388357	01/18/2012 03/05/2013	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
6.	APPARATUS FOR TESTING ELECTRONIC DEVICES	13754765 8506335	01/30/2013 08/13/2013	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
7.	APPARATUS FOR TESTING ELECTRONIC DEVICES	13939364 8628336	07/11/2013 01/14/2014	Silicon Valley Bank Reel/Frame 033743/0852 Recorded 09/16/2014
8.	APPARATUS FOR TESTING ELECTRONIC DEVICES	14097541 8747123	12/05/2013 06/10/2014	Silicon Valley Bank Reel/Frame 033743/0852 Recorded 09/16/2014
9.	APPARATUS FOR TESTING ELECTRONIC DEVICES	14263826 20140232424	04/28/2014	Silicon Valley Bank Reel/Frame 033743/0852 Recorded 09/16/2014
10.	ASSEMBLY FOR ELECTRICALLY CONNECTING A TEST COMPONENT TO A TESTING MACHINE FOR TESTING	10197104 6867608	07/16/2002 03/15/2005	Silicon Valley Bank Reel/Frame 031171/0001 Recorded

	Title	Application No. / Publication No. / Patent No.	Filing Date / Issue Date	Security Interest
	ELECTRICAL CIRCUITS ON THE TEST COMPONENT			09/06/2013
11.	ASSEMBLY FOR ELECTRICALLY CONNECTING A TEST COMPONENT TO A TESTING MACHINE FOR TESTING ELECTRICAL CIRCUITS ON THE TEST COMPONENT	10912785 7046022	08/06/2004 05/16/2006	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
12.	ASSEMBLY FOR ELECTRICALLY CONNECTING A TEST COMPONENT TO A TESTING MACHINE FOR TESTING ELECTRICAL CIRCUITS ON THE TEST COMPONENT	11433845 7385407	05/12/2006 06/10/2008	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
13.	ASSEMBLY FOR ELECTRICALLY CONNECTING A TEST COMPONENT TO A TESTING MACHINE FOR TESTING ELECTRICAL CIRCUITS ON THE TEST COMPONENT	12045480 7511521	03/10/2008 03/10/2008	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
14.	CONNECTOR	29327294 D630166	11/03/2008 01/04/2011	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
15.	CONTACTOR ASSEMBLY FOR TESTING ELECTRICAL CIRCUITS	10197133 6853209	07/16/2002 02/08/2005	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
16.	CONTACTOR ASSEMBLY FOR TESTING ELECTRICAL CIRCUITS	10971897 7301358	10/22/2004 11/27/2007	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
17.	DIE CARRIER	10245934 6859057	09/17/2002 02/22/2005	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
18.	DIE CARRIER	11032846 7126363	01/10/2005 10/24/2006	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
19.	ELECTRONICS TESTER WITH A SIGNAL DISTRIBUTION BOARD AND A WAFER CHUCK HAVING DIFFERENT COEFFICIENTS OF THERMAL EXPANSION	12062988 7667475	04/04/2008 02/23/2010	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
20.	ELECTRONICS TESTER WITH A SIGNAL DISTRIBUTION BOARD AND A WAFER CHUCK HAVING	12684051 7902846	01/07/2010 03/08/2011	Silicon Valley Bank Reel/Frame 031171/0001

	Title	Application No. / Publication No. / Patent No.	Filing Date / Issue Date	Security Interest
	DIFFERENT COEFFICIENTS OF THERMAL EXPANSION			Recorded 09/06/2013
21.	ELECTRONICS TESTER WITH A SIGNAL DISTRIBUTION BOARD AND A WAFER CHUCK HAVING DIFFERENT COEFFICIENTS OF THERMAL EXPANSION	13022803 8198909	02/08/2011 06/12/2012	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
22.	ENHANCEMENTS IN TESTING DEVICES ON BURN-IN BOARDS	09407659 6292415	09/28/1999 09/18/2001	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
23.	INTEGRATED FEEDTHROUGH MODULE	13168910 20110256774	06/24/2011	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
24.	INTERFACE ON AN ELECTRONICS CONNECTOR	29327293 D629760	11/03/2008 12/28/2010	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
25.	KINEMATIC COUPLING	09353123 6413113	07/14/1999 07/02/2002	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
26.	METHOD AND SYSTEM FOR TESTING MEMORY PROGRAMMING DEVICES	08407103 5682472	03/17/1995 10/28/1997	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
27.	RELOADING OF DIE CARRIERS WITHOUT REMOVAL OF DIE CARRIERS FROM SOCKETS ON TEST BOARDS	10940288 7303929	09/13/2004 12/04/2007	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
28.	REUSABLE DIE CARRIER FOR BURN-IN AND BURN-IN PROCESS	08948696 6025732	05/06/1997 02/15/2000	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
29.	SEPARATE TEST ELECTRONICS AND BLOWER MODULES IN AN APPARATUS FOR TESTING AN INTEGRATED CIRCUIT	12437465 7969175	05/07/2009 06/28/2011	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
30.	SYSTEM FOR BURN-IN TESTING OF ELECTRONIC DEVICES	10184525 6815966	06/27/2002 11/09/2004	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
31.	SYSTEM FOR BURN-IN TESTING	10917139	08/11/2004	Silicon Valley Bank

	Title	Application No. / Publication No. / Patent No.	Filing Date / Issue Date	Security Interest
	OF ELECTRONIC DEVICES	7063544	06/20/2006	Reel/Frame 031171/0001 Recorded 09/06/2013
32.	SYSTEM FOR TESTING AN INTEGRATED CIRCUIT OF A DEVICE AND ITS METHOD OF USE	11960453 7800382	12/19/2007 09/21/2010	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
33.	SYSTEM FOR TESTING AN INTEGRATED CIRCUIT OF A DEVICE AND ITS METHOD OF USE	12411233 8030957	03/25/2009 10/04/2011	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
34.	SYSTEM FOR TESTING AN INTEGRATED CIRCUIT OF A DEVICE AND ITS METHOD OF USE	12885373 8228085	09/17/2010 07/24/2012	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
35.	SYSTEM FOR TESTING AN INTEGRATED CIRCUIT OF A DEVICE AND ITS METHOD OF USE	13223319 8947116	09/01/2011 02/03/2015	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
36.	SYSTEM FOR TESTING AN INTEGRATED CIRCUIT OF A DEVICE AND ITS METHOD OF USE	13554722 20120280704	07/20/2012	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
37.	SYSTEM FOR TESTING AND BURNING IN OF INTEGRATED CIRCUITS	11013855 7053644	12/15/2004 05/30/2006	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
38.	WAFER BURN-IN AND TEST EMPLOYING DETACHABLE CARTRIDGE	09884537 6556032	06/18/2001 04/29/2003	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
39.	WAFER BURN-IN AND TEST EMPLOYING DETACHABLE CARTRIDGE	10396170 7088117	03/24/2003 08/08/2006	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
40.	WAFER BURN-IN AND TEST EMPLOYING DETACHABLE CARTRIDGE	11276314 7541822	02/23/2006 06/02/2009	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
41.	WAFER LEVEL BURN-IN AND ELECTRICAL TEST SYSTEM AND METHOD	09353121 6562636	07/14/1999 05/13/2003	Silicon Valley Bank Reel/Frame 031171/0001 Recorded

	Title	Application No. / Publication No. / Patent No.	Filing Date / Issue Date	Security Interest
				09/06/2013
42.	WAFER LEVEL BURN-IN AND ELECTRICAL TEST SYSTEM AND METHOD	09885957 6682945	05/25/2001 01/27/2004	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
43.	WAFER LEVEL BURN-IN AND ELECTRICAL TEST SYSTEM AND METHOD	10718825 7619428	11/21/2003 11/17/2009	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
44.	WAFER LEVEL BURN-IN AND ELECTRICAL TEST SYSTEM AND METHOD	12574447 7928754	10/06/2009 04/19/2011	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
45.	WAFER LEVEL BURN-IN AND TEST METHODS	09353116 6580283	07/14/1999 06/17/2003	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
46.	WAFER LEVEL BURN-IN AND TEST THERMAL CHUCK AND METHOD	09161323 6140616	09/25/1998 10/31/2000	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
47.	WAFER-LEVEL BURN-IN AND TEST CARTRIDGE	09353214 6340895	07/14/1999 01/22/2002	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
48.	PRINTED CIRCUIT BOARD LOADER/UNLOADER	07/526069 5093984	5/18/1990 3/10/1992	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
49.	REUSABLE DIE CARRIER FOR BURN-IN AND BURN-IN PROCESS	08/089752 5517125	7/9/1993 5/14/1996	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
50.	HIGH-DENSITY INTERCONNECT TECHNIQUE	08/161282 5429510	12/1/1993 7/4/1995	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
51.	APPARATUS FOR TESTING ELECTRONIC DEVICES	12/772932 8118618	5/3/2010 2/21/2012	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013

	Title	Application No. / Publication No. / Patent No.	Filing Date / Issue Date	Security Interest
52.	APPARATUS FOR TESTING ELECTRONIC DEVICES	13/754765 20130141135	1/30/2013 6/6/2013	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
53.	APPARATUS FOR TESTING ELECTRONIC DEVICES	13/353269 20120113556	1/18/2012 5/10/2012	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
54.	SYSTEM FOR TESTING AN INTEGRATED CIRCUIT OF A DEVICE AND ITS METHOD OF USE	13/223319 20110316577	9/1/2011 12/29/2011	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
55.	ELECTRONICS TESTER WITH A SIGNAL DISTRIBUTION BOARD AND A WAFER CHUCK HAVING DIFFERENT COEFFICIENTS OF THERMAL EXPANSION	13/022803 20110156745	2/8/2011 6/30/2011	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
56.	ASSEMBLY FOR ELECTRICALLY CONNECTING A TEST COMPONENT TO A TESTING MACHINE FOR TESTING ELECTRICAL CIRCUITS ON THE TEST COMPONENT	12/045480 20080150560	3/10/2008 6/26/2008	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
57.	SYSTEM FOR TESTING AN INTEGRATED CIRCUIT OF A DEVICE AND ITS METHOD OF USE	12/885373 20110006800	9/17/2010 1/13/2011	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
58.	SEPARATE TEST ELECTRONICS AND BLOWER MODULES IN AN APPARATUS FOR TESTING AN INTEGRATED CIRCUIT	12/437465 20100283475	5/7/2009 11/11/2010	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
59.	SYSTEM FOR TESTING AN INTEGRATED CIRCUIT OF A DEVICE AND ITS METHOD OF USE	12/411233 20100244866	3/25/2009 9/30/2010	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
60.	APPARATUS FOR TESTING ELECTRONIC DEVICES	12/772932 20100213957	5/3/2010 8/26/2010	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
61.	ELECTRONICS TESTER WITH A SIGNAL DISTRIBUTION BOARD AND A WAFER CHUCK HAVING DIFFERENT COEFFICIENTS OF	12/684051 20100109696	1/7/2010 5/6/2010	Silicon Valley Bank Reel/Frame 031171/0001 Recorded

	Title	Application No. / Publication No. / Patent No.	Filing Date / Issue Date	Security Interest
	THERMAL EXPANSION			09/06/2013
62.	SYSTEM FOR TESTING AN INTEGRATED CIRCUIT OF A DEVICE AND ITS METHOD OF USE	11/960453 20090160468	12/19/2007 6/25/2009	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
63.	ELECTRONICS TESTER WITH A SIGNAL DISTRIBUTION BOARD AND A WAFER CHUCK HAVING DIFFERENT COEFFICIENTS OF THERMAL EXPANSION	12/062988 20090015282	4/4/2008 1/15/2009	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013
64.	WAFER LEVEL BURN-IN AND ELECTRICAL TEST SYSTEM AND METHOD	10/718825 20040113645	11/21/2003 6/17/2004	Silicon Valley Bank Reel/Frame 031171/0001 Recorded 09/06/2013